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N-Channel Super Junction Power MOSFET $\, \mathrm{I\!V}$

General Description

The series of devices use advanced trench gate super junction technology and design to provide excellent R_{DS(ON)} with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

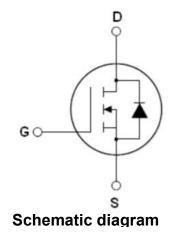
Features

- New technology for high voltage device
- Low on-resistance and low conduction losses
- ●Small package
- ●Ultra Low Gate Charge cause lower driving requirements
- ●100% Avalanche Tested
- ROHS compliant

Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)

V _{DS min@Tjmax}	710	V
R _{DS(ON)TYP} .	30	mΩ
I_D	70	Α
Qg	102	nC



Package Marking And Ordering Information

Device	Device Package	Marking	
NCE65NF036T	TO-247	NCE65NF036T	



Table 1. Absolute Maximum Ratings (T_c=25℃)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (Vgs=0V)	V _{DS}	650	V
Gate-Source Voltage (V _{DS=0} V) ,AC (f>1 Hz)	Vgs	±30	V
Continuous Drain Current at Tc=25°C	I _{D (DC)}	70	А
Continuous Drain Current at Tc=100°C	I _{D (DC)}	49	А
Pulsed drain current (Note 1)	I _{DM (pluse)}	210	А
Maximum Power Dissipation(Tc=25℃)	P_{D}	488	W
Derate above 25°C		3.25	W/°C
Single pulse avalanche energy (Note 2)	Eas	2117	mJ
Single pulse avalanche current (Note 2)	I _{AS}	11	А
Repetitive Avalanche energy $, t_{AR}$ limited by T_{jmax} (Note 1)	E _{AR}	0.9	mJ
Reverse diode dv/dt, V _{DS} ≤480 V,I _{SD} <i<sub>D</i<sub>	dv/dt	50	V/ns
Drain Source voltage slope,V _{DS} ≤480 V	dv/dt	50	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55+175	°C



Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	0.31	°C /W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	62	°C /W

 Table 3. Electrical Characteristics (TA=25℃unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states	•			•		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =1mA	650			V
Zero Gate Voltage Drain Current(Tc=25℃)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			10	μΑ
Zero Gate Voltage Drain Current(Tc=125°C)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			400	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V			±200	nA
Gate Threshold Voltage	V _{GS(th)}	$V_{DS}=V_{GS},I_{D}=3mA$	3	4	5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =35A		30	36	mΩ
Dynamic Characteristics						
Gate Resistance	Rg	F=1MHZ, D-S short		4		Ω
Input Capacitance	C _{lss}	V -50VVV 0V		6287		pF
Output Capacitance	Coss	V_{DS} =50V, V_{GS} =0V,		263		pF
Reverse Transfer Capacitance	C _{rss}	F=1MKHz		15.1		pF
Total Gate Charge	Qg			102	108	nC
Gate-Source Charge	Q _{gs}	\		37		nC
Gate-Drain Charge	Q_{gd}	V _{DS} =400V,I _D =40A,V _{GS} =10V		22		nC
Gate plateau voltage	Vgp			6		V
Switching times						
Turn-on Delay Time	t _{d(on)}			54		nS
Turn-on Rise Time	t _r	V _{DD} =380V,I _D =40A,		37		nS
Turn-Off Delay Time	t _{d(off)}	$R_G=4\Omega,V_{GS}=10V$		127		nS
Turn-Off Fall Time	t _f			5		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T 05°0			70	Α
Pulsed-Source-drain current(Body Diode)	I _{SDM}	T _C =25°C			210	Α
Forward on voltage	V _{SD}	Tj=25°C,I _{SD} =70A,V _{GS} =0V		1.0	1.2	V
Reverse Recovery Time	t _{rr}	T: 05°C ! 404		185		nS
Reverse Recovery Charge	Qrr	Tj=25°C,I _F 40A,		1.6		uC
Peak reverse recovery current	I _{rrm}	di/dt=100A/μs		16		Α

Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. Tj=25°C,VDD=50V,VG=10V, R_G=25 Ω , L=35mH



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure 1. Safe operating area

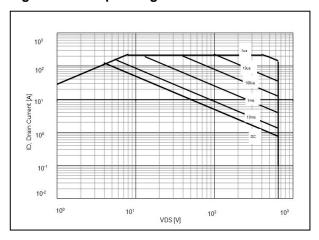


Figure 2. Source-Drain Diode Forward Voltage

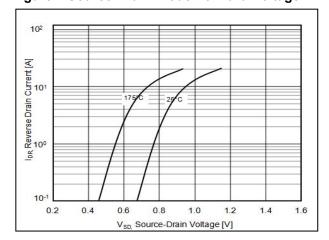


Figure3. Output characteristics (25℃)

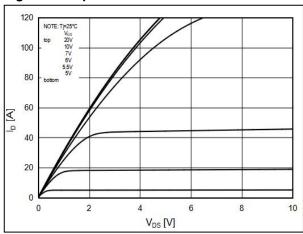


Figure4. Output characteristics (100℃)

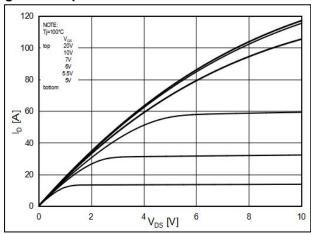


Figure 5. Transfer characteristics

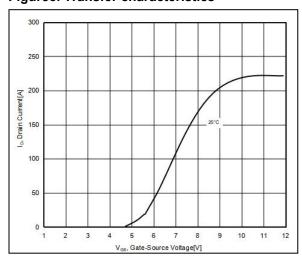


Figure 6. Static drain-source on resistance

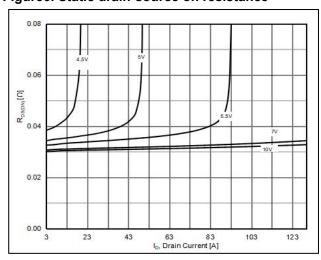




Figure 7. R_{DS(ON)} vs Junction Temperature

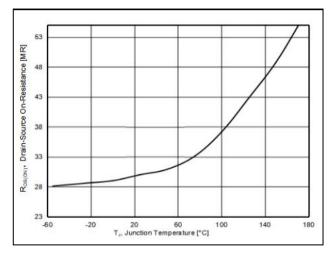


Figure 9. Maximum ID vs Junction Temperature

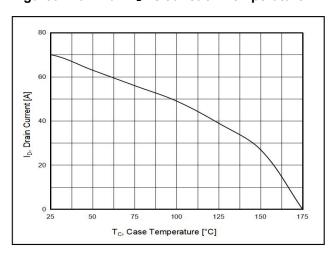


Figure11. Capacitance

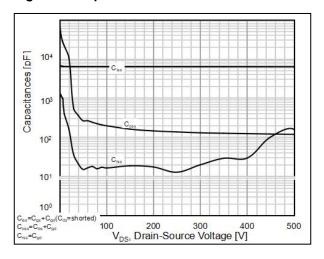


Figure8. BV_{DSS} vs Junction Temperature

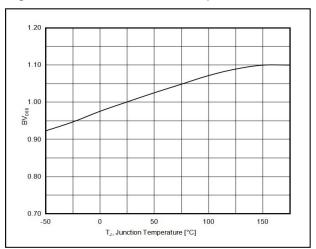
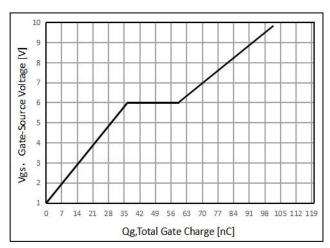


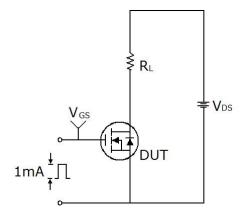
Figure 10. Gate charge waveforms

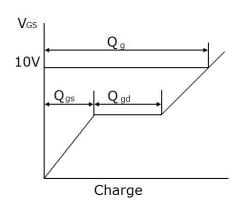




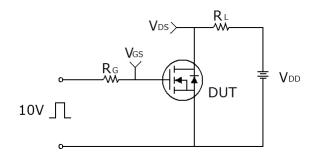
Test circuit

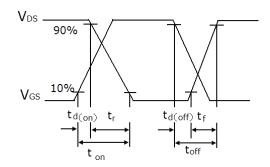
1) Gate charge test circuit & Waveform



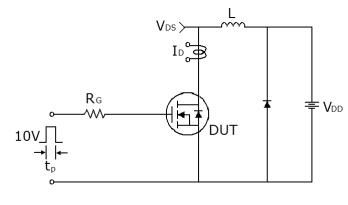


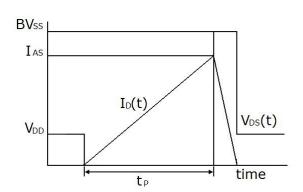
2) Switch Time Test Circuit:





3) Unclamped Inductive Switching Test Circuit & Waveforms

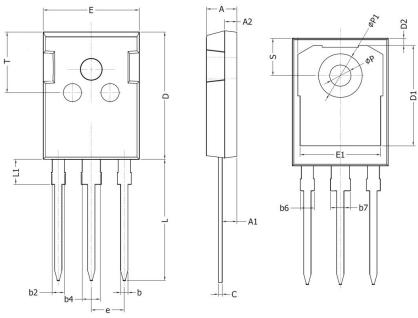




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TO-247 (P) Package Information

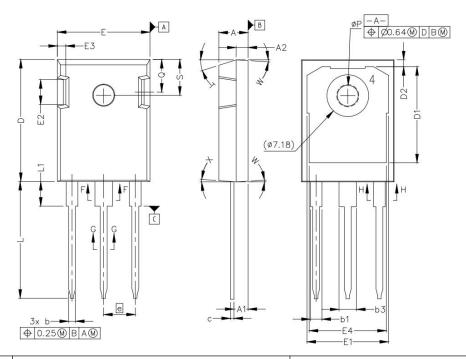


Compleal	Dimensions I	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	4.90	5.10	0.193	0.201	
A1	2.31	2.51	0.091	0.099	
A2	1.90	2.10	0.075	0.083	
b	1.16	1.26	0.046	0.050	
b2	1.96	2.06	0.077	0.081	
b4	2.96	3.06	0.117	0.120	
b6	-	2.25	-	0.089	
b7	-	3.25	-	0.128	
С	0.59	0.66	0.023	0.026	
D	20.90	21.10	0.823	0.831	
D1	16.25	16.85	0.640	0.663	
D2	1.05	1.35	0.041	0.053	
E	15.70	15.90	0.618	0.626	
E1	13.10	13.50	0.516	0.531	
е	5.436	5.436 BSC 0.214 BSC		BSC	
L	19.80	20.10	0.780	0.791	
L1	-	4.30	-	0.169	
Р	3.40	3.60	0.134	0.142	
P1	7.00	7.40	0.276	0.291	
S	6.05	6.25	0.238	0.246	
Т	9.80	10.20	0.386	0.402	

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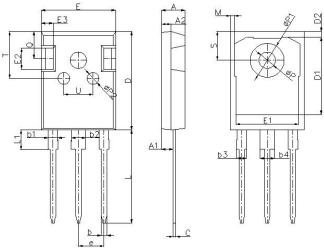
TO-247-B Package Information



Cymphal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
Α	4.83	5.21	0.190	0.205	
A1	2.29	2.54	0.090	0.100	
A2	1.91	2.16	0.075	0.085	
b	1.07	1.33	0.042	0.052	
b1	1.91	2.41	0.075	0.095	
b3	2.87	3.38	0.113	0.133	
С	0.55	0.68	0.022	0.027	
D	20.80	21.10	0.819	0.831	
D1	16.25	17.65	0.640	0.695	
D2	0.95	1.25	0.037	0.049	
E	15.75	16.13	0.620	0.635	
E1	13.10	14.15	0.516	0.557	
E2	3.68	5.10	0.145	0.201	
E3	1.00	1.90	0.039	0.075	
E4	12.38	13.43	0.487	0.529	
е	5.44	BSC	0.214	BSC	
N	3.	00	0.118		
L	19.81	20.32	0.780	0.800	
L1	4.10	4.40	0.161	0.173	
Р	3.51	3.65	0.138	0.144	
Q	5.49	6.00	0.216	0.236	
S	6.04	6.30	0.238	0.248	



TO-247-E Package Information



Completel	Dimensions I	n Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	4.90	5.10	0.193	0.201	
A1	2.31	2.51	0.091	0.099	
A2	1.90	2.10	0.075	0.083	
b	1.16	1.26	0.046	0.050	
b1	1.96	2.06	0.077	0.081	
b2	2.96	3.06	0.117	0.120	
b3	-	2.25	-	0.089	
b4	-	3.25	-	0.128	
С	0.59	0.66	0.023	0.026	
D	20.90	21.10	0.823	0.831	
D1	16.25	16.85	0.640	0.663	
D2	1.05	1.35	0.041	0.053	
E	15.70	15.90	0.618	0.626	
E1	13.10	13.50	0.516	0.531	
E2	4.40	4.60	0.173	0.181	
E3	2.40	2.60	0.094	0.102	
е	5.436	BSC	0.214BSC		
L	19.80	20.10	0.780	0.791	
L1	-	4.30	-	0.169	
М	0.35	0.95	0.014	0.037	
Р	3.40	3.60	0.134	0.142	
P1	7.00	7.40	0.276	0.291	
P2	2.40	2.60	0.094	0.102	
Q	5.60	6.00	0.220	0.236	
S	6.05	6.25	0.238	0.246	
Т	9.80	10.20	0.386	0.402	
U	6.00	6.40	0.236	0.252	



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